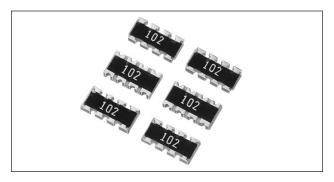
CRA, CRB, CRC Series





Chip Resistor Arrays have several resistor elements integrated as a single component.

4 Element Array:

CRA3A4E Series Convex Scallop Type
CRB3A4E Series Concave Type
CRC3A4E Series Convex Corner Type

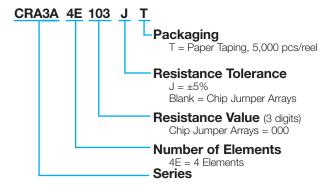
FEATURES

- Reduction in mounting process & costs
- Save PCB space
- Reduction of inventory control costs

APPLICATIONS

- Computer
- Hard Disk Drive
- Printer CD-ROM

HOW TO ORDER



RATING

TATING					
Chip Resistor Arrays		Chip Jumper Arrays			
Item	Rating	Item	Rating		
Rated Power (70°C)*	1/16W Element				
Max. Working Voltage	50V	Rated Current	1A		
Max. Overload Voltage	100V				
Resistance Value	$J = 10\Omega$ to $2.2M\Omega$	Conductive	F00		
Tolerance	J±5%	Resistance Value	50m $Ω$ max.		
Working Temperature	-55 to +125°C				
Number of Elements	4E = 4 Elements				

^{*}Rated voltage = 50V or $\sqrt{\text{Rated power x Resistance value}}$, whichever is less

DIMENSIONS

millimeters (inches)

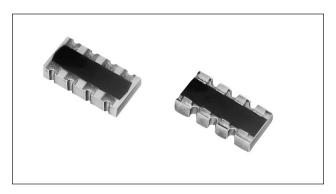
	minimo esta financia						
	4 Elements CRA3A4E Series	4 Elements CRB3A4E Series	4 Elements CRC3A4E Series				
Style	C U						
W	1.60±0.15 (0.063±0.006)	1.60±0.15 (0.063±0.006)	1.60±0.15 (0.063±0.006)				
L	3.20±0.15 (0.126±0.006)	3.20±0.15 (0.126±0.006)	3.20±0.15 (0.126±0.006)				
С	0.30±0.20 (0.012±0.008)	0.30±0.20 (0.012±.0008)	0.30±0.20 (0.012±0.008)				
d	0.20±0.15 (0.008±0.006)	0.40±0.15 (0.016±0.006)	0.20±0.15 (0.008±0.006)				
t	0.50±0.10 (0.020±0.004)	0.60±0.10 (0.024±0.004)	0.50±0.10 (0.020±0.004)				
р	0.80 typ (0.031)	0.80 typ (0.031)	0.80 typ (0.031)				

Detailed specifications are available on request.



CRB 2A4E, CRC 2A4E Series





4 Element Chip Resistor Array:

CRB2A4E Series (凹 Termination)

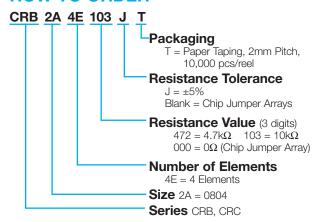
CRC2A4E Series (凸 Termination)

Ultra miniature chip resistor arrays have 4 resistor elements integrated as a single component.

FEATURES

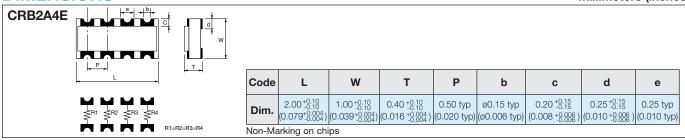
- Miniature (2.0x1.0mm) Resistor Arrays
 Max. 60% space saving compared with the use of standard chip array (3.2x1.6mm)
- 0.5mm Termination pitch (same as IC lead-pin pitch)
 Easy designing of pattern layout and improve electrical characteristics for circuit

HOW TO ORDER

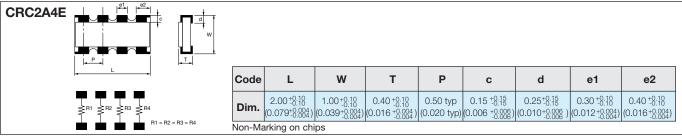


DIMENSIONS

millimeters (inches)



DIMENSIONS millimeters (inches)



RATING

Chip Resistor Arrays		Chip Jumper Arrays				
Item	Rating	Item	Rating			
Rated Power (70°C)	1/32W Element		1A			
Max. Working Voltage*	25V	Rated Current				
Max. Overload Voltage	50V					
Resistance Value	10 Ω to 1M Ω	Conductive	50m $Ω$ max.			
Tolerance	$J = \pm 5\%$	Resistance Value	JOHNSZ MAX.			
Working Temperature	-55 to +125°C					
Number of Elements	4E = 4 Elements					

^{*}Please contact sales engineer for any other requirements of the nominal resistance value and the tolerance.

^{*}Rated voltage = $\sqrt{\text{Rated power x Resistance value, whichever is less}}$





CR, CJ, CRA, CRB, CRC Series - Test Conditions

ELECTRICAL CHARACTERISTICS

Item		Standard		Test Conditions	
		Resistor	Jumper	Resistor	Jumper
DC Resist	tance	Within Initial Tolerance	50mΩ max.	Power Condition A (20°C, 65% RH)	
Temperature Characteristics		$\begin{tabular}{ c c c c c c c c c c c c c c c c c c c$		Test Temperature: 25, 125(°C) Δ R/R=R ₂ -R ₁ /R ₁ x1/T ₂ -T ₁ x10 ⁶ Δ R/R = Temp. Coefficient (ppm/°C) T ₁ = 25(°C) T ₂ = 125(°C) R ₁ = T ₁ Resistance at (Ω) R ₂ = T ₂ Resistance at (Ω)	
Short-time Overload	ΔR/R	\pm (2.0%+0.10 Ω) max. of the initial value	50m Ω max.	 (1) Apply 2.0 x rated voltage for 5 sec. (2.5 x rated voltage for Arrays) (2) Wait 30 minutes (3) Measure resistance CR05 = 50V max. CR10 = 100V max. CR21 = 200V max. CR32 = 400V max. CRA, CRB, CRC = 100V max. 	(1) 2A for 5 sec. (2) Wait 30 minutes (3) Measure resistance
	Visual No evidence of mechanical damage intermittent overload				
Intermittent Overload	ΔR/R	\pm (5%+0.1 Ω) max. of the initial value	50mΩ max.	(1) Perform 10,000 voltage cycles as follows: ON (2.0 x rated voltage, 2.5 x for Arrays) 1 sec. OFF 25 sec. (2) Stabilization time 30 min. without loading (3) Measure resistance CR05 = 50V max. CR10 = 150V max.	(1) Perform 10,000 current cycles as follows: ON (2A) 1 sec. OFF 25 sec. (2) Wait 30 minutes (3) Measure resistance
	Visual	No evidence of mechanical damage		CR21 = 200V max. CR32 = 400V max. CRA, CRB, CRC = 100V max.	
	Dielectric Withstanding Voltage No evidence of mechanical damage		Apply 500 VAC for 1 min. (CR10 300 VAC) (CR05, CRA, CRB, CRC 300 VAC/1 sec.)		
Insulation Resistance		• CR05, CJ05 = $10^{9}\Omega$ min. • CR10, CJ10 = $10^{9}\Omega$ min. • CR21, CJ21 = $10^{10}\Omega$ min. • CR32, CJ32 = $10^{12}\Omega$ min. • CRA, CRB, CRC = $10^{9}\Omega$ min.		Apply 500V DC (CR05, CRA, CRB, CRC 100V DC)	





CR, CJ, CRA, CRB, CRC Series - Test Conditions

MECHANICAL CHARACTERISTICS

Item		Standard		Test Conditions		
		Resistor	Jumper	Resistor	Jumper	
	ΔR/R	$\pm (1\% + 0.05 \Omega)$ max. of the initial value	50mΩ max.	Apply the load as shown: Measure resistance during load application		
Terminal Strength	Visual	No evidence of mechanical damage after loading		Bending in 10 seconds PC Board = Glass epoxy t = 1.60 (0.063)		
Soldering Heat	ΔR/R	$\pm (1\% + 0.05\Omega)$ max. of the initial value	50m $Ω$ max.	Immerse into molten solder at 260±5°C for 10±1 se Stabilize component at room temperature for 1 hr.		
Resistance	Visual	No evidence of leaching		Measure resistance.		
Solderability		Coverage ≥95% each termination end		Immerse in Rogin Flux for 2±0.5 sec. and in SN62 solder at 235±5°C for 2±0.5 sec.		
Anti-Vibration	ΔR/R	$\pm (1\% + 0.1\Omega)$ max. of the initial value	50mΩ max.	2 hrs. each in X, Y and Z axis. (TTL 6 hrs.) 10 to 55 Hz sweep in 1 min. at 1.5mm amplitude.		
Test	Visual	No evidence of mechanical damage				
Solvent Resistance	ΔR/R	$\pm (0.5\% + 0.05\Omega)$ max. of the initial value	50m $Ω$ max.	Immerse in static state butyl acetate at 20°C to 25° for 30±5 sec. Stabilize component at room temperature for 30 mi		
	Visual	No evidence of mechanical damage		then measure value.		

ENVIRONMENTAL CHARACTERISTICS

ENVIRONMENTAL CHARACTERISTICS							
Item		Standard		Test Conditions			
		Resistor	Jumper	Resistor	Jumper		
Temperature Cycle	Δ R/R	$\pm (1\% + 0.05\Omega)$ max. of the initial value	50mΩ max.	(1) Run 5 cycles as follows: -55±: 125±3°C for 30 min. Room to	emp. for 10-15 min.		
	Visual	No evidence of mechanical damaç	No evidence of mechanical damage		temperature for 1 hr.		
Low Temperature	ΔR/R	$\pm (2\% + 0.1\Omega)$ max. of the initial value	50mΩ max.	(1) Dwell in -55°C chamber without loading for 100 hrs.			
Storage	Visual	No evidence of mechanical damage		(2) Stabilize component at room then measure value.	(2) Stabilize component at room temperature for 1 hr. then measure value.		
High Temperature	Δ R/R	$\pm (3\% + 0.1\Omega)$ max. of the initial value	50mΩ max.	(1) Dwell in 125°C chamber without loading for hrs.			
Storage	Visual	No evidence of mechanical damage		(2) Stabilize component at room temperature for 1 then measure value.			
Moisture	ΔR/R	$\pm (3\% + 0.1\Omega)$ max. of the initial value	50m $Ω$ max.	(1) Dwell in temp.: 65°C RH90 to 95% RH characteristics without loading for 1000 +48 hrs.			
Resistance	Visual	No evidence of mechanical dama	No evidence of mechanical damage		temperature for 1 hr.		
Life Test	Δ R/R	$\pm (3\% + 0.1\Omega)$ max. of the initial value	50m $Ω$ max.	(1) Temp.: 70±3°C Voltage: (rate off 30 min. Duration: 1000 ±48	hrs.		
	Visual	No evidence of mechanical dama	No evidence of mechanical damage		temperature for 1 hr.		
Loading Life in Moisture	ΔR/R	$\pm (3\% + 0.1\Omega)$ max. of the initial value	50m $Ω$ max.	(1) Temp.: 40±2°C RH: 90-95% min. (rated voltage) off 30 min.	Duration: 1000 +48 hrs.		
	Visual	No evidence of mechanical dama	No evidence of mechanical damage		temperature for 1 hr.		

